

Form 1449 <i>OIPC</i> APR 23 2001 PATENT & TRADEMARK OFFICE		U.S. Department of Commerce Patent and Trademark Office		Docket No.: <b>P01,0008</b>	Serial No. <b>09/762,508</b>
		LIST OF PRIOR ART CITED BY APPLICANT (use several sheets if necessary)		Applicant(s): <b>Joachim Baumann et al.</b>	
				Filing Date <b>February 7, 2001</b>	Group Art Unit <b>2881</b>

## U.S. PATENT DOCUMENTS

Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If appropriate
<i>AN</i>	AA	5,206,710	27 April 1993	Geiler et al			
<i>GR</i>	AB	4,875,175	17 October 1989	Egee et al			
<i>GR</i>	AC	4,513,384	23 April 1985	Rosencwaig			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>AN</i>	AJ	DE 196 46 947	14 May 1998	Germany				
<i>GR</i>	AK	EP 0 735 378	02 October 1996	Europe				
<i>AN</i>	AL	DE 195 20 788	18 July 1996	Germany				
<i>GR</i>	AM	DE 42 03 272 A1	12 August 1993	Germany				
<i>GR</i>	AN	DE 42 03 272 C2	18 May 1995	Germany				
<i>AN</i>	AO	DE 40 35 266	07 May 1992	Germany				
<i>GR</i>	AP	DE 36 31 652	24 March 1989	Germany				
<i>GR</i>	AO	EP 0 233 120	19 August 1987	Europe				

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>GR</i>	AR	WAGNER, M et al; "Single-beam thermowave analysis of ion implanted and laser annealed semiconductors", Measurement Science & Technology, (1991), Vol. 2, No. 11, Bristol, GB, pgs. 1088-1093.
<i>GR</i>	AS	WAGNER, M. et al; "Nondestructive Measuring and Testing with Optically Excited Thermal Waves", Laser & Optoelektronik, (1994), Vol. 26, No. 1, pgs. 63-68.
	AT	
	AU	
	AV	
	AW	

Examiner *AN* Date Considered *9-26-02*  
*ALBERT GAGLIARDI*

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.